

Notice of References Cited	Application/Control No. 10/568,947		Applicant(s)/Patent Under Reexamination MUTO ET AL.	
	Examiner Hai H. Huynh		Art Unit 3747	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-7,200,486 B2	04-2007	Tanaka et al.	701/109
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NON-PATENT DOCUMENTS

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